

DESCRIPTION

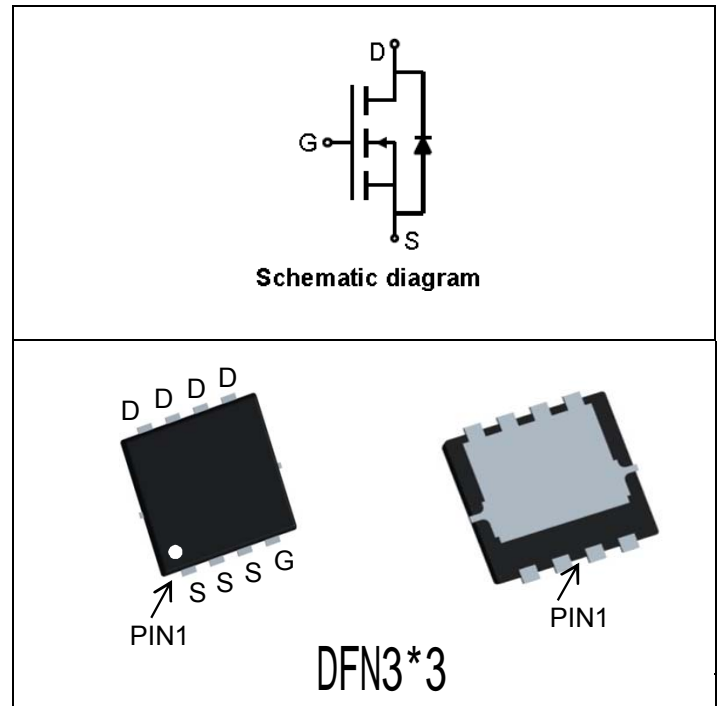
The 3075 uses advanced trench technology to provide excellent $R_{DS(ON)}$ and low gate charge. This device is suitable for use as a load switch or in PWM applications.

GENERAL FEATURES

- $R_{DS(ON)} < 8\text{m}\Omega @ V_{GS}=4.5\text{V}$
 $R_{DS(ON)} < 5\text{m}\Omega @ V_{GS}=10\text{V}$
- High Power and current handling capability
- Lead free product is acquired
- Surface Mount Package

Application

- PWM applications
- Load switch
- Power management



■ Absolute Maximum Ratings ($T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-source Voltage	V_{DS}	30	V
Gate-source Voltage	V_{GS}	± 20	V
Drain Current	I_D	$T_C=25^\circ\text{C}$	30
		$T_C=100^\circ\text{C}$	21
Pulsed Drain Current ^A	I_{DM}	120	A
Total Power Dissipation	P_D	$T_C=25^\circ\text{C}$	35
		$T_C=100^\circ\text{C}$	15
Single Pulse Avalanche Energy ^B	E_{AS}	29	mJ
Thermal Resistance Junction-to-Case ^C	$R_{\theta JC}$	3.4	$^\circ\text{C}/\text{W}$
Junction and Storage Temperature Range	T_J, T_{STG}	-55~+150	$^\circ\text{C}$

ELECTRICAL CHARACTERISTICS (T_A=25°C unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Static Parameter						
0V, V						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0V, I _D =250μA	30			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =24V, V _{GS} =0V	T _J =25°C		1	μA
			T _J =55°C		10	
Gate-Body Leakage Current	I _{GSS}	V _{GS} = ±20V, V _{DS} =0V			±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D =250μA	1.2	1.5	2.2	V
Static Drain-Source On-Resistance	R _{DS(ON)}	V _{GS} = 10V, I _D =15A		4.1	5.0	mΩ
		V _{GS} = 4.5V, I _D =15A		6.5	8.0	
Diode Forward Voltage	V _{SD}	I _S =1 A, V _{GS} =0V		0.7	1.2	V
Maximum Body-Diode Continuous Current	I _S				30	A
Dynamic Parameters						
Input Capacitance	C _{iss}	V _{DS} =15V, V _{GS} =0V, f=1MHZ		990		pF
Output Capacitance	C _{oss}			550		
Reverse Transfer Capacitance	C _{rss}			60		
Switching Parameters						
Total Gate Charge	Q _g	V _{GS} =10V, V _{DS} =15V, I _D =20A		14.7		nC
Gate-Source Charge	Q _{gs}			2.2		
Gate-Drain Charge	Q _{gd}			3.1		
Reverse Recovery Charge	Q _{rr}	I _S =20A, V _{GS} =0V, di/dt=100A/μS		25		ns
Reverse Recovery Time	t _{rr}			26		
Turn-on Delay Time	t _{D(on)}	V _{DS} =15V, I _D =15A, R _G =3.0 Ω V _{GS} =10V		TBC		ns
Turn-on Rise Time	t _r			TBC		
Turn-off Delay Time	t _{D(off)}			TBC		
Turn-off fall Time	t _f			TBC		

A. Pulse Test: Pulse Width ≤300μs, Duty cycle ≤2%.

B. T_J=25°C, V_{DS}=20V, V_G=10V, L=0.5mH, R_g=25 Ω

C. R_{θJA} is the sum of the junction-to-case and case-to-ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{θJC} is guaranteed by design, while R_{θJA} is determined by the board design. The maximum rating presented here is based on mounting on a 1 in 2 pad of 2oz copper.

■ Typical Performance Characteristics

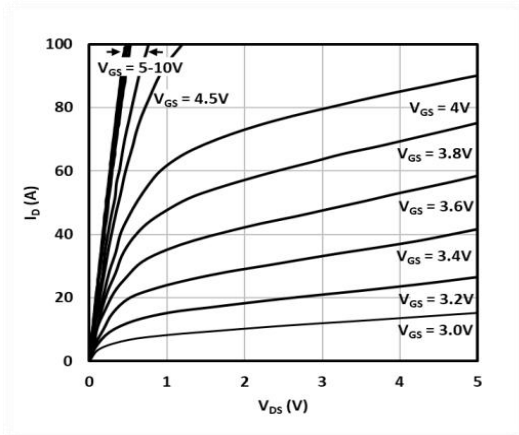


Figure1. Output Characteristics

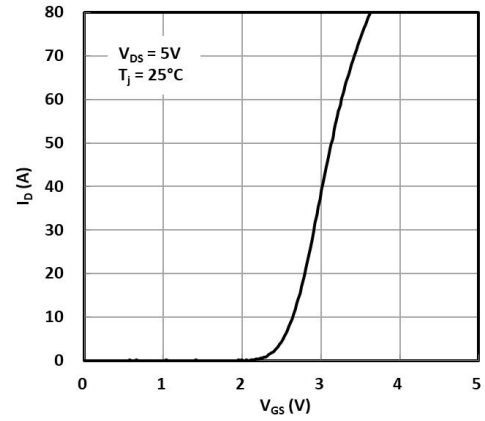
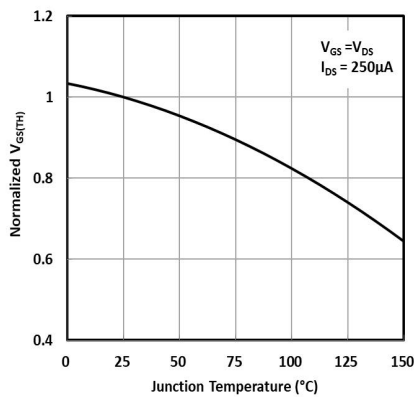
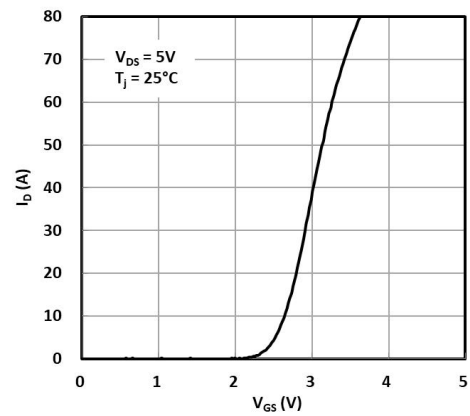


Figure2. Transfer Characteristics



Figur3.Normalized gate threshold voltage vs. temperature



Figur4.On-resistance vs. gate voltage

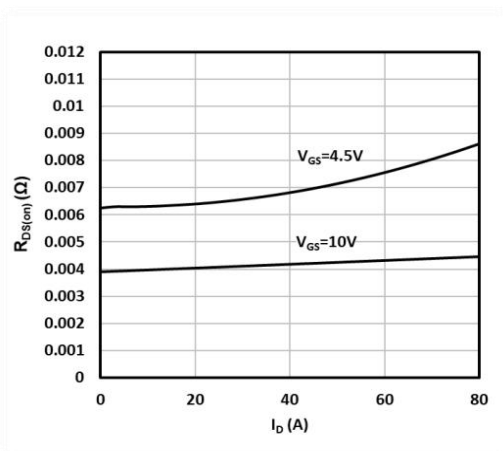


Figure5. Drain-Source on Resistance

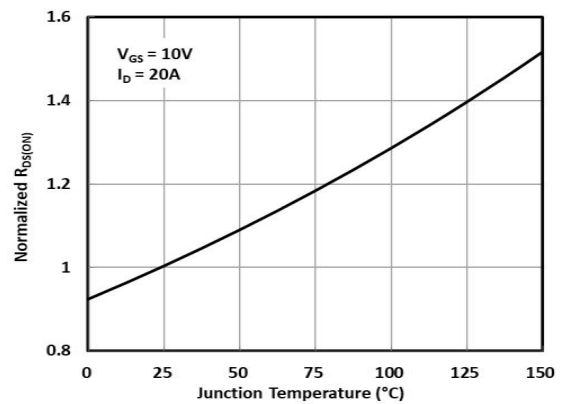
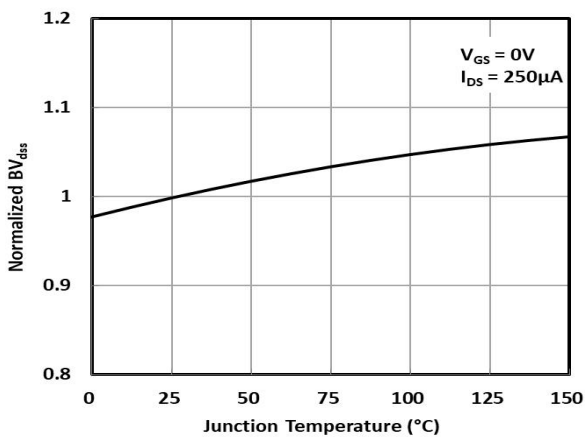
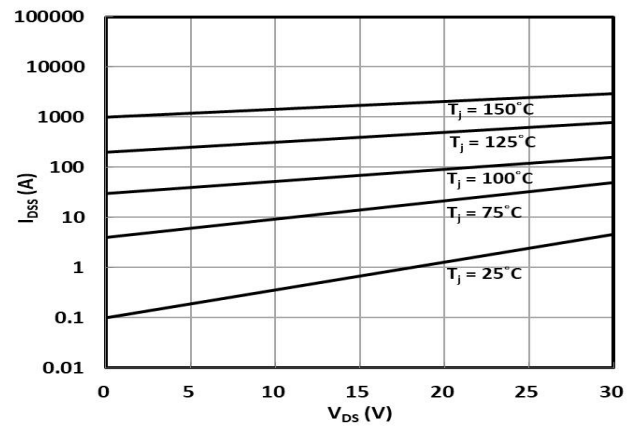


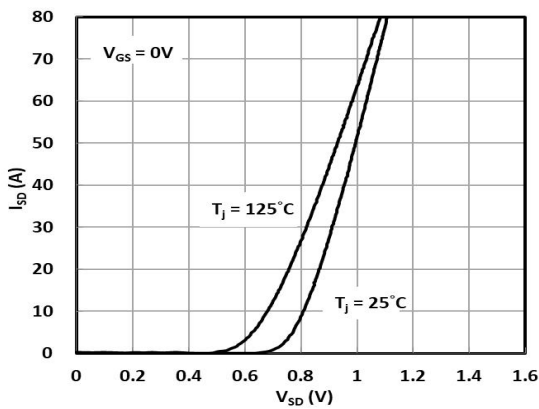
Figure6. Drain-Source on Resistance



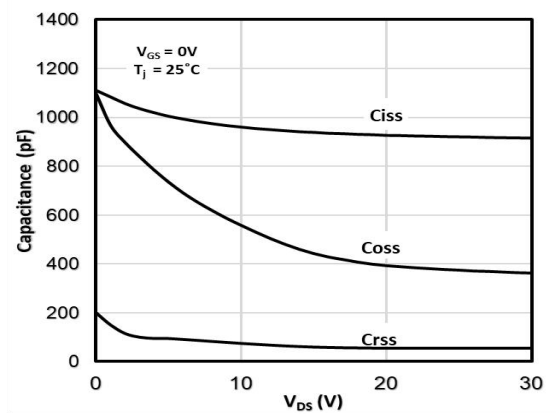
Figur7. Normalized drain-to-source breakdown voltage vs. temperature



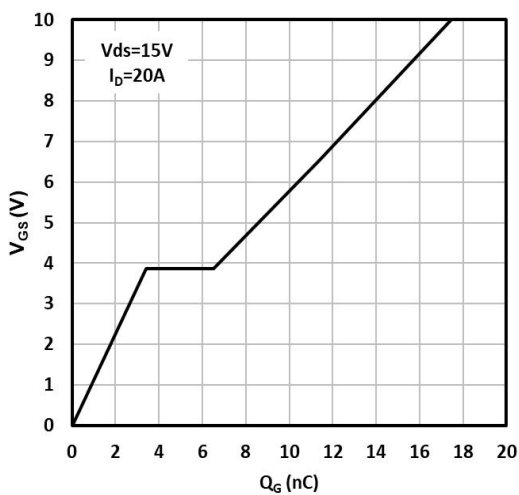
Figur8. Drain-to-source leakage current vs. voltage



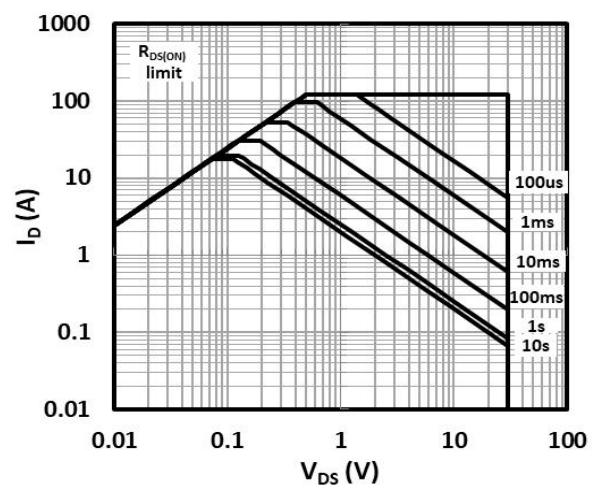
Figur9. Source-to-drain diode forward characteristics



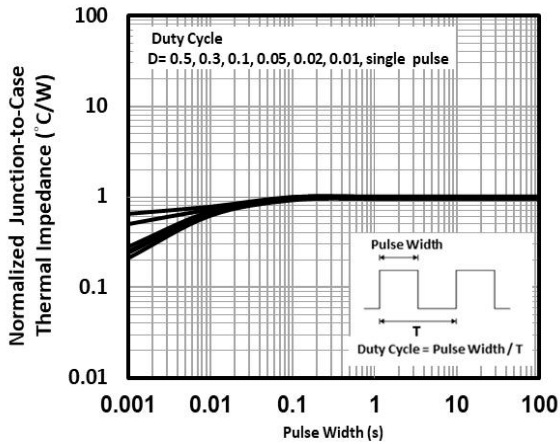
Figur10. Capacitance vs. drain-to-source voltage



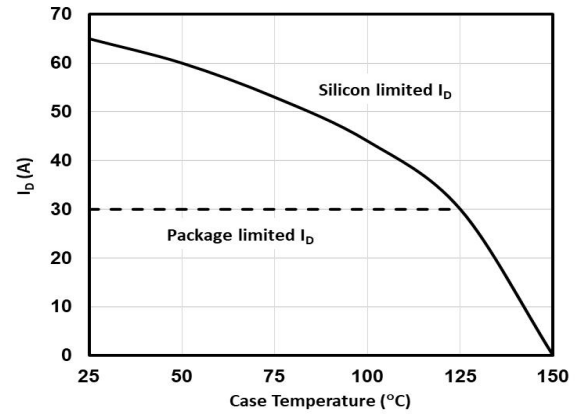
Figur11. Gate-to-source voltage vs. gate charge



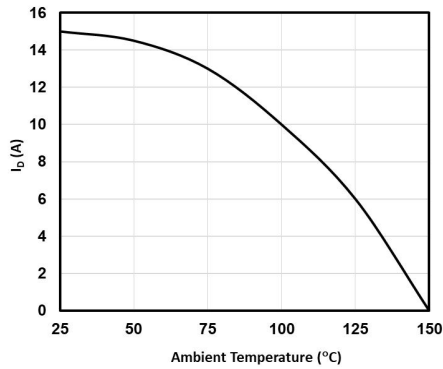
Figur12. Safe operating area



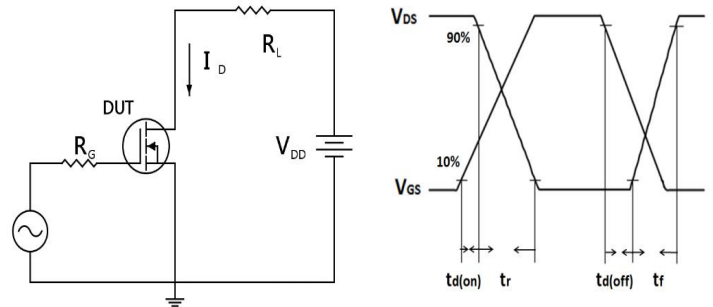
Figur13. Junction-to-case thermal impedance



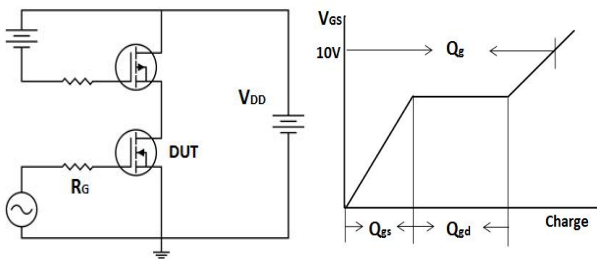
Figur14. Maximum drain current vs .case temperature



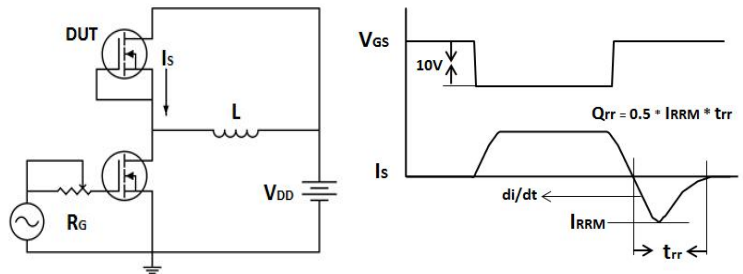
Figur15. Maximum drain current vs .ambient temperature



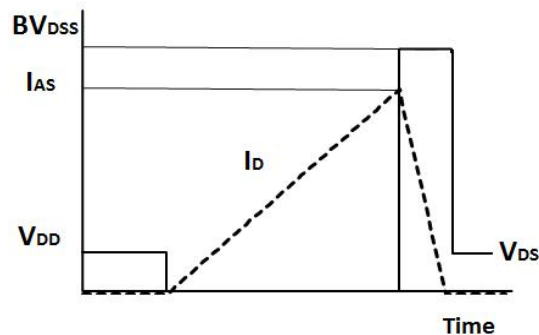
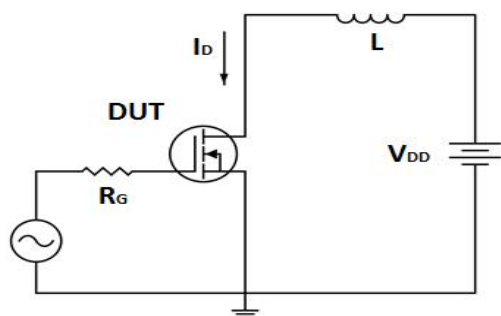
Resistive switching time test circuit&waveforms



Gate charge test circuit&waveform



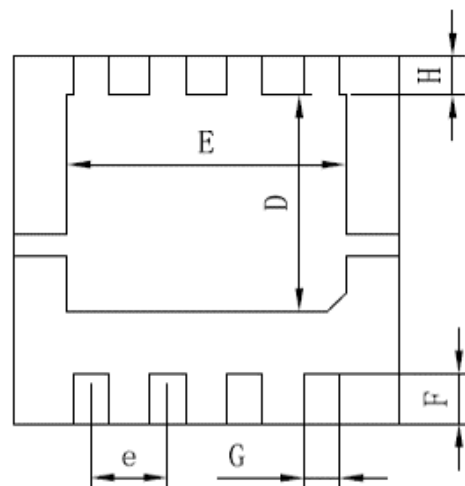
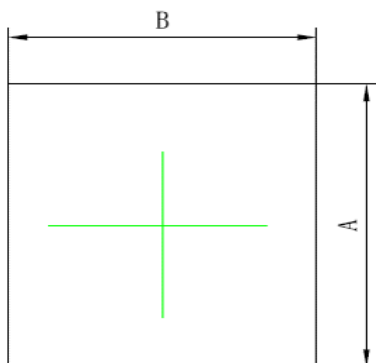
Peak diode recovery dv/dt test circuitD& waveforms



Unclamped inductive switching test circuit & waveforms

Package Information

■ DFN3.3X3.3 Package information



A	B	C	C1
3.25±0.05	3.25±0.05	0.8±0.05	0.2±0.02
C2	D	E	F
0.05Max	1.9±0.1	2.35±0.15	0.45±0.05
G	H	e	
0.3±0.05	0.35±0.05	0.65±0.05	
单位: mm			

